WANSEMI
万芯半导体

WP30H50APA

Enhancement Mode N-Channel Power MOSFET

PDFN5x6/NMOS/30V/±20V/1.9V/150A/2.75mΩ

Rev0.6

30V, 2.75mΩ, 150A, Single N-Channel

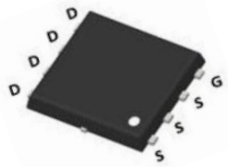
1.Features

- 30V MOSFET technology
- Low on-state resistance
- Fast switching
- Vgs±20V

V_{DS}	$R_{DS(on)}$ Typ.	I_D Max.
30V	2.75mΩ @ 10V	150A
	4.1mΩ @ 4.5V	

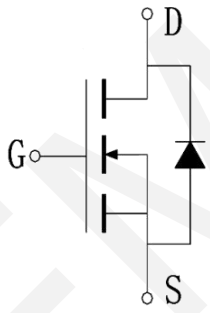
2.Applications

- Power Switching Application
- Load Switching



PDFN5x6

Pin Description



Schematic Diagram

3.Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Reel	PCS/CTN.
WP30H50APA	WP30H50APA	PDFN5X6	5,000	50,000

4.Absolute Max Ratings at Ta=25℃ (Note1)

Parameter	Symbol	Maximum	Units
Drain to Source Voltage	V_{DSS}	30	V
Gate to Source Voltage	V_{GSS}	±20	V
Drain Current (DC)	I_D	150	A
Drain Current (Pulse), PW≤300μs	I_{DP}	480	A
Total Dissipation	P_D	57	W
Avalanche Energy, Single Pulsed	E_{AS}	225	mJ
Junction Temperature	T_j	150	℃
Storage Temperature	T_{stg}	-55 to +150	℃

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

5.Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to case	$R_{\theta JC}$	2.2	℃/W

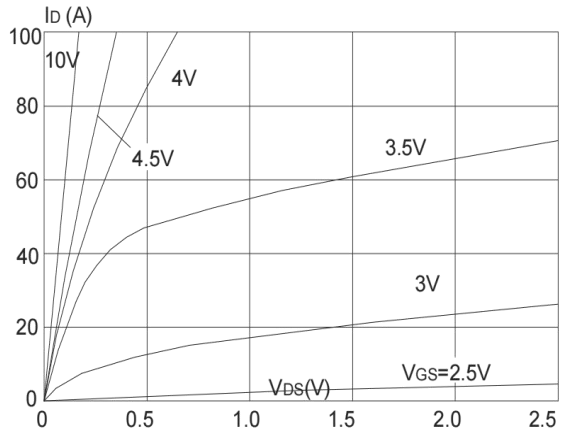
Note 2： When mounted on 1 inch square copper board t ≤ 10sec The value in any given application depends on the user's specific board design.

6.Electrical Characteristics at Ta=25℃ (Note 3)

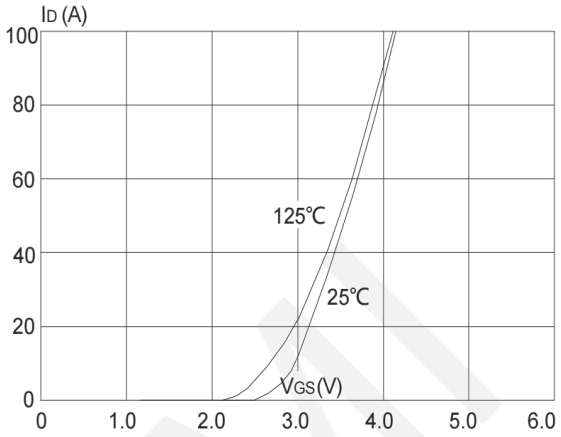
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	I_D = 250μA, V_{GS} = 0V	30			V
Zero-Gate Voltage Drain Current	I_{DSS}	V_{DS} =30V, V_{GS} = 0V			1	μA
Gate to Source Leakage Current	I_{GSS}	V_{GS} = ±20V, V_{DS} = 0V			±100	nA
Gate Threshold Voltage	$V_{GS(th)}$	V_{DS}=V_{GS}, I_{DS}=250μA	1.0	1.9	2.5	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	I_D = 30A, V_{GS} = 10V	-	2.75	3.2	mΩ
		I_D = 20A, V_{GS} = 4.5V	-	4.1	5.3	mΩ
Input Capacitance	C_{iss}	V_{GS}=0V, V_{DS}=15V, Frequency=1.0MHz		4930		pF
Output Capacitance	C_{oss}			682		pF
Reverse Transfer Capacitance	C_{rss}			566		pF
Turn-ON Delay Time	$t_{d(on)}$	V_{DD} = 15V, I_D = 30A, V_{GS} = 10V, R_{GEN} =3Ω		17		ns
Rise Time	t_r			137		ns
Turn-OFF Delay Time	$t_{d(off)}$			63		ns
Fall Time	t_f			113		ns
Total Gate Charge	Q_g	V_{DD} = 15V, V_{GS} = 10V, I_D = 30A		93		nC
	Q_{gs}			15		nC
	Q_{gd}			23		nC
Diode Forward Voltage	V_{FSD}	I_S =30A, V_{GS} = 0			1.2	V

Note 3： Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

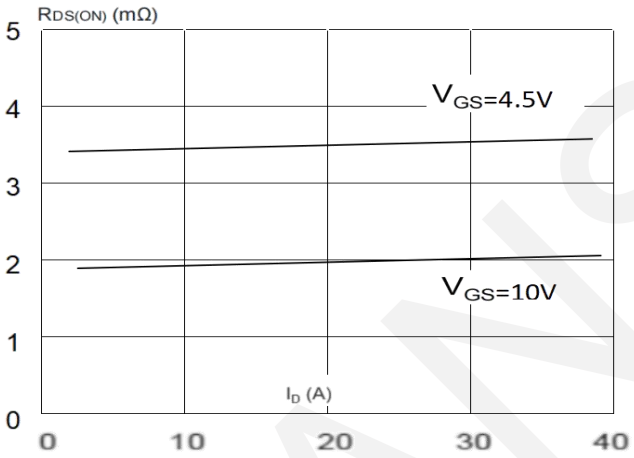
7.Typical electrical and thermal characteristics



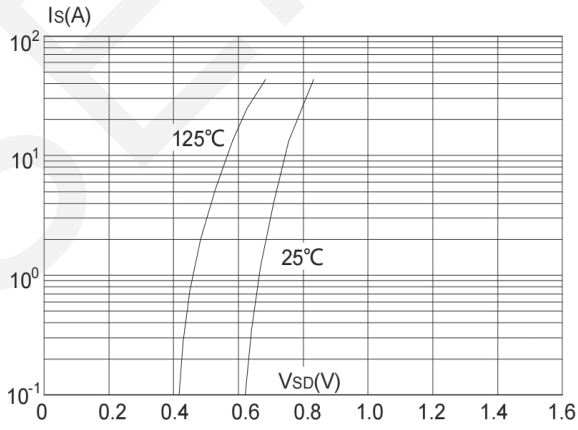
Output Characteristics



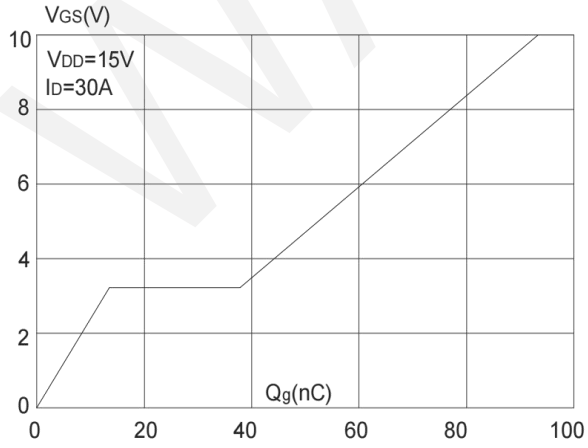
Typical Transfer Characteristics



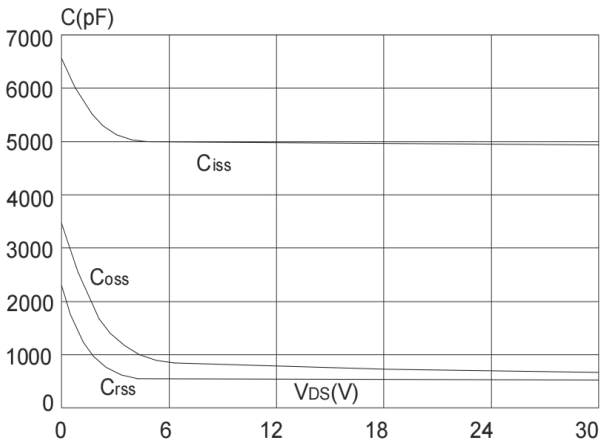
On-resistance vs. Drain Current



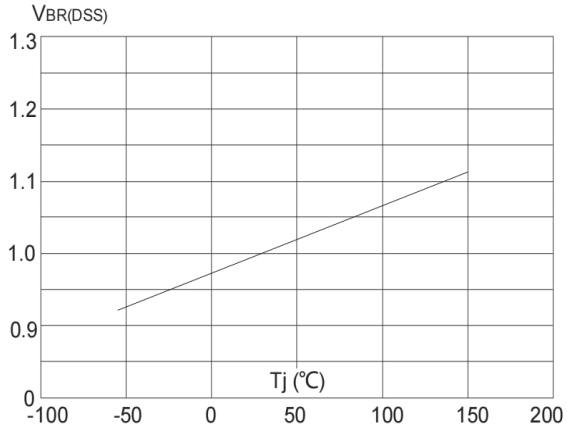
Body Diode Characteristics



Gate Charge Characteristics

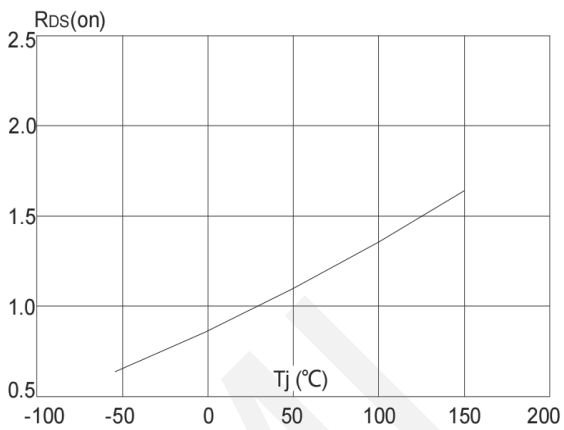


Capacitance Characteristics



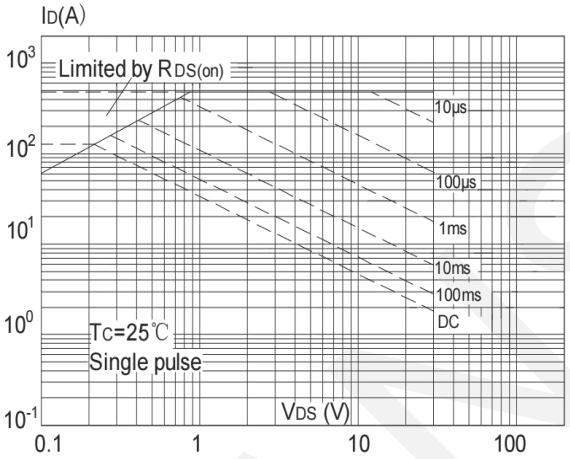
Normalized Breakdown Voltage vs.

Junction Temperature

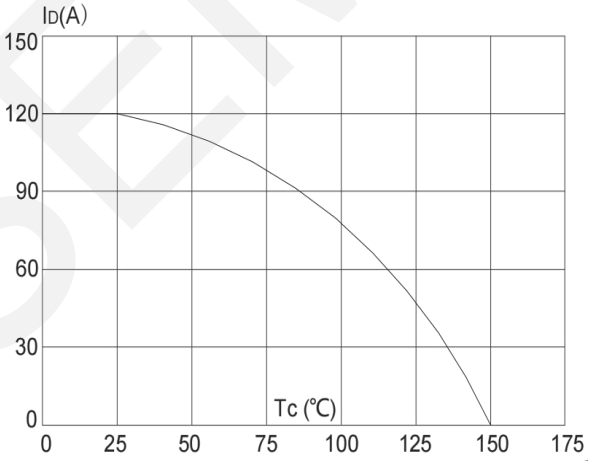


Normalized on Resistance vs.

Junction Temperature

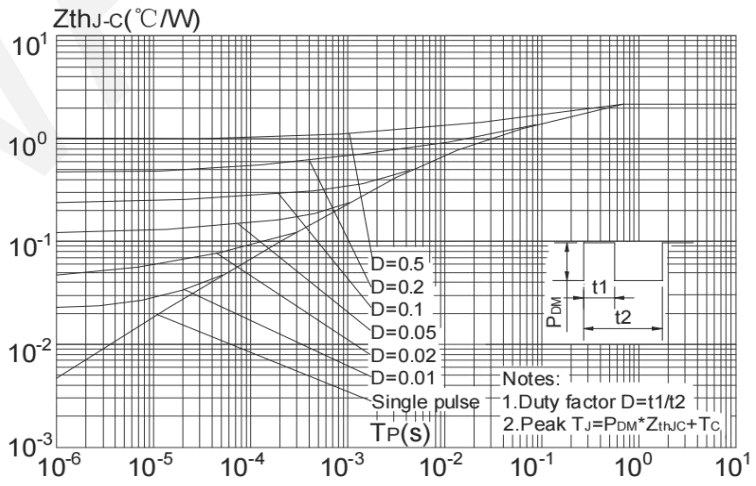


Maximum Safe Operating Area



Maximum Continuous Drain Current vs.

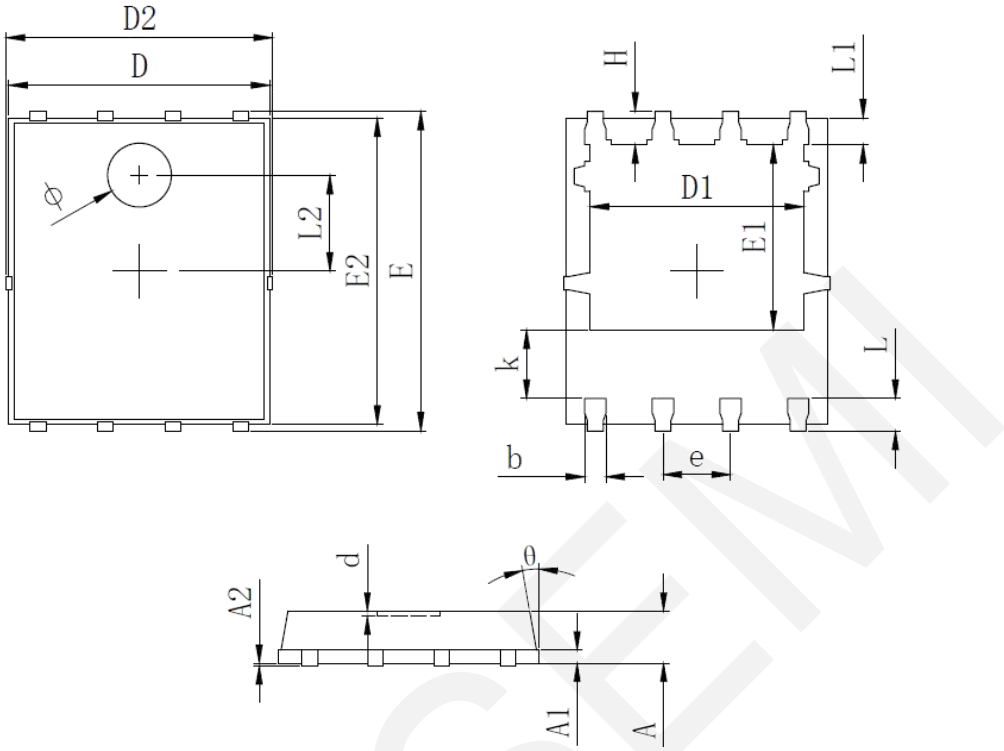
Case Temperature



Maximum Effective Transient

Thermal Impedance, Junction-to-Case

8.Package Dimensions



SYMBOL	MILLIMETER		
	MIN	Typ.	MAX
A	0.900	1.000	1.100
A1	0.254 REF.		
A2	0~0.05		
D	4.824	4.900	4.976
D1	3.910	4.010	4.110
D2	4.924	5.000	5.076
E	5.924	6.000	6.076
E1	3.375	3.475	3.575
E2	5.674	5.750	5.826
b	0.350	0.400	0.450
e	1.270 TYP.		
L	0.534	0.610	0.686
L1	0.424	0.500	0.576
L2	1.800 REF.		
k	1.190	1.290	1.390
H	0.549	0.625	0.701
θ	8°	10°	12°
ϕ	1.100	1.200	1.300
d			0.100

9. Important Notice

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